Search Notes

Application	/Control No.	Applicant(s) Reexaminat	/Patent under ion	
10/501,302		NEUPART,	LARS	
Examiner		Art Unit		
Shin-Hon C	Chen	2131		

SEARCHED			
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	INTERFERENCE SEARCHED					
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
USPAT, PGPUB, DERWENT, JPO, EPO (BRS search- see search history)	6/29/2007	S.C.	
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